

DC FAN LIFE EXPERIMENT REPORT

DG10FNL062 30616.50		6.50	201	6/10/10	Dong(Qian.Liang	Tim.Yi	
QE File No.	Time-out for function test or others (hours)			ed Date	Reported By		Approved By	
					Test	t Result	✓ □	Accept Reject
3. Noise cannot >3dB over	er the origina	l measure no	oise.					
 Speed can not drop of Current cannot increas 	70	1.00	134,693	19,242				
Fan permission criteria fo					60	2.00	269,386	38,484
					50	4.00	538,772	76,967
failures, it should be used in a	repairable syste	m seung.			40	8.00	1,077,544	153,935
will not repair the failed fans d	uring life exper	iment. MTBF:			30	16.00	2,155,088	307,870
greater than the warrant. (MT non-repairable system setting.					25	22.63	3,047,755	435,394
Herewith, we could assume as test time exceed the required, i	-				Temperature for MTTF Estimation (℃)	Acceleration Factor ${f A_F}$	Estimated MTTF (hours)	Estimated L ₁₀ (hours)
2010/5/22 3:30]	Date for Test Termination (at least) 2011/11/22 7:06 PM		☐ In process	In process (exceed requested)	☐ Termination	25360.0		
Date for Test Beginning			C	urrent Test St	rrent Test Status		Current Total Test Time (hours)	
Test Progress:								
70	40	8.00	15	2.303	13,180	25,360.0	1,077,544	153,935
Stress/Elevated Temperature Ts (℃) (Actual Test Temperature)	Unstress Temperature Tu (°C)	Acceleration Factor A _F	Quantity of Test Devices n (pcs)	Poisson Distribution Factor B _{r;c}	Required test time with zero failure t (hours)	Actual test time with zero failure t (hours)	Verified MTTF 40 ℃ (hours)	Verified L ₁₀ 40 °C (hours)
the decimal confidence le	vel of c equal	l to 0.90(90%	6).	T	ſ		Γ	T
where, (B _{r;c}) is Poisson di	stribution fac	tor with the	failure numl	ber of r equal to	0 and			
		$t = 1.036 \times N$	MTTF×[(B _r	$_{\rm sc}$)÷ ${\rm n}$] $^{0.91}$ ÷ ${\rm A}_{\rm F}$, a	and $A_F = 2^{(Ts-T)}$	u)/10		
the total test time (t) for v				_	1 /			
And we rely on a zero fail				ated testing tech			200,000	nours
L₁₀ Expectancy:According to the equation	for Weihul	-		mum @ 1an rat		i tne temperature ≒ 7×L10 =	560,000	hours
Equipment: 1.0ven: E24-	On/Off Cycles: Every 500 hours							
Representative Test P/N:		-9E1Y						
THB 208x208x70.0 mm series as								
Available for these models with lower speed and same physical structure. All model may be followed byRxx orFxx series suffixes. This test report applies to				THB2048CT				
0	awar spood and se	ama physical str	acturo All	THB2048CTAXK				
DELTA ELECTRONICS, INC.								

BGN (dBA):16.1 Temp (°C):24.8



DC FAN FUNCTION TEST RECORD

FOR LIFE EXPERIMENT

Available f	or these models	with lower chee	d and came nhy	reical etructura	THB2048CTAXK				
Available for these models with lower speed and same physical structure. All model may be followed byRxx orFxx series suffixes. This test report applies to THB 208x208x70.0 mm series as the right table					THB2048CT				
applies to	ГНВ 208x208x7	0.0 mm series as	s the right table	;					
Required Test Date for Time (hrs) Begin		7 2 2 3 2 3 3 3 3 3 3 3 3 3 3 3 3 3 3 3		or Test nation	Sample Size (pcs):	Failure (pcs):	Current Total Test Time (hrs) 25360.0		
13	13,180 2010/5/22 3:30 PM		2011/11/22 7:06 PM						
Representative Test P/N: THB2048CT-9E			1Y Current To		est Status	In process	In process (exceed requested)	Termination	
Equipme	ent: 1.Oven	: E24-T016	9				On/Off Cycles:	Every 500 ho	urs
			Test I	Data Between	n Initial Tes	t and Final	Test		
Sample	Initial Test Current Spec.	Final Test Current Spec.	Deviation	Initial Test Speed Spec.	Final Test Speed Spec.	Deviation	Initial Test Noise Spec.	Final Test Noise Spec.	Deviation
No.	(A)	(A)	(%)	(RPM)	(RPM)	(%)	(dB A)	(dB A)	
	5.88 Max.	5.88 Max.		5220-6380	5220-6380		79.5 Max	79.5 Max	3 dBMax.
1	5. 27	4.95	-6.0	5961	5844	-2.0	75.1	73.4	-1.7
2	5.30	4.98	-5.9	5973	6018	0.8	75.4	73.7	-1.7
3	5. 32	4.94	-7.2	5988	5814	-2.9	75.6	73.6	-2.0
4	5. 22	4.96	-5.1	5992	5934	-1.0	75.3	73.5	-1.8
5	5. 21	4.98	-4.5	5985	6017	0.5	75.2	73.3	-1.9
6	5. 13	4.94	-3.7	5952	5877	-1.3	75.5	73.8	-1.7
7	5. 33	4.94	-7.3	5994	5872	-2.0	75.4	73.6	-1.8
8	5. 35	4.93	-7.9	5907	5865	-0.7	75.6	73.2	-2.4
9	5. 24	4.98	-5.1	6015	5984	-0.5	75.4	73.3	-2.1
10	5.32	4.94	-7.1	5936	5899	-0.6	75.2	73.4	-1.8
11	5.21	5.01	-3.9	6022	6016	-0.1	75.6	73.0	-2.6
12	5. 23	5.01	-4.2	5952	5901	-0.9	75.1	73.6	-1.5
13	5.31	5.01	-5.7	5972	6065	1.6	75.4	73.6	-1.8
14	5. 20	4.99	-4.0	6024	5953	-1.2	75.5	73.5	-2.0
15	5.21	5.00	-4.0	5983	5960	-0.4	75.3	73.0	-2.3
X-Bar	5.256	4.970	-	5977.1	5934.6	-	75.37	73.43	-
σ	0.062	0.029	-	32.228	74.656	-	0.171	0.238	-
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